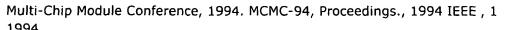
### IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs	
IEEE X	Welcome United States Patent and Trademark Of
Help: FAQ Terms IEE Review	<u>Peers</u> Source Links St
Welcome to IEEE Xplore  - Home - What Can I Access? - Log-out	Your search matched 16 of 933812 documents. Results are shown 15 to a page, sorted by publication year in descending order.  Results: Journal or Magazine = JNL Conference = CNF Standard = STD
Tables of Contents  Journals & Magazines  Conference Proceedings Standards  Search By Author Basic Advanced  Member Services Join IEEE Establish IEEE Web Account  Access the IEEE Member Digital Library  Print Format	1 Transport considerations in porous low k and metal interconnect syapproaching atomic dimensions  Thomas, M.E.; Smith, D.M.; Wallace, S.; Iwamoto, N.;  Interconnect Technology Conference, 2002. Proceedings of the IEEE 2002  International, 2002  Page(s): 223-225
	[Abstract] [PDF Full-Text (302 KB)] <b>IEEE CNF</b> 2 <b>Precision electrical trimming of very low TCR poly-SiGe resistors</b> Babcock, J.A.; Francis, P.; Bashir, R.; Kabir, A.E.; Schroder, D.K.; Lee, M.S.;  Dhayagude, T.; Yindeepol, W.; Prasad, S.J.; Kalnitsky, A.; Thomas, M.E.; Have Egan, K.; Bergemont, A.; Jansen, P.;  IEEE Electron Device Letters, Volume: 21 Issue: 6, Jun 2000  Page(s): 283 -285
	[Abstract] [PDF Full-Text (56 KB)] IEEE JNL  3 Atmospheric thermal lensing in laser resonators  Barnes, N.P.; Thomas, M.E.; Koch, G.J.; Marsh, W.B.;  Quantum Electronics, IEEE Journal of, Volume: 31 Issue: 5, May 1995  Page(s): 962 -969  [Abstract] [PDF Full-Text (712 KB)] IEEE JNL  4 Design Of Manufacturing Strategy With Wafer Cost Estimation  Saadat, I.A.; Thomas, M.E.; Gattiker, A.; Maly, W.;
	Saadat, I.A.; Thomas, M.E.; Gattiker, A.; Maly, W.; Semiconductor Manufacturing, 1994. Extended Abstracts of ISSM '94. 1994 International Symposium on , 21-22 Jun 1994 Page(s): 57 -60

[Abstract] [PDF Full-Text (452 KB)] IEEE CNF

5 Are there any alternatives to " known g od die" ? [MC Gattiker, A.E.; Maly, W.; Thomas, M.E.;

۴



Page(s): 102 -107

### [Abstract] [PDF Full-Text (540 KB)] IEEE CNF

## 6 Extraction of defect size distributions in an IC layer using test strudata

Khare, J.B.; Maly, W.; Thomas, M.E.; Semiconductor Manufacturing, IEEE Transactions on , Volume: 7 Issue: 3 , A Page(s): 354 -368

### [Abstract] [PDF Full-Text (1360 KB)] IEEE JNL

### 7 Smart-substrate multichip-module systems

Maly, W.; Feltham, D.B.I.; Gattiker, A.E.; Hobaugh, M.D.; Backus, K.; Thom Design & Test of Computers, IEEE, Volume: 11 Issue: 2, Summer 1994 Page(s): 64-73

### [Abstract] [PDF Full-Text (836 KB)] IEEE JNL

# 8 Extraction of defect characteristics for yield estimation using the d bridge test structure

Khare, J.B.; Daniels, B.J.; Campbell, D.M.; Thomas, M.E.; Maly, W.; VLSI Technology, Systems, and Applications, 1991. Proceedings of Technical 1991 International Symposium on , 22-24 May 1991 Page(s): 428 -432

### [Abstract] [PDF Full-Text (452 KB)] IEEE CNF

### 9 Multilevel microcoaxial interconnect: a novel technology for VLSI microwave circuits

Thomas, M.E.; Saadat, I.A.; Sekigahama, S.; VLSI Multilevel Interconnection Conference, 1991, Proceedings., Eighth Intel IEEE, 11-12 Jun 1991
Page(s): 116-122

### [Abstract] [PDF Full-Text (768 KB)] IEEE CNF

### 10 VLSI multilevel micro-coaxial interconnects for high speed device:

Thomas, M.E.; Saadat, I.A.; Sekigahama, S.; Electron Devices Meeting, 1990. Technical Digest., International, 9-12 Dec 1990 Page(s): 55-58

### [Abstract] [PDF Full-Text (304 KB)] IEEE CNF

### 11 Issues associated with the use of electroless copper films for submultilevel interconnections

Thomas, M.E.; Sekigahama, S.; Myers, S.A.;

VLSI Multilevel Interconnection Conference, 1990. Proceedings., Seventh Int

IEEE , 12-13 Jun 1990

Page(s): 335 -337

### [Abstract] [PDF Full-Text (428 KB)] **IEEE CNF**

# 12 The mechanical planarization of interlevel dielectrics for multileve interconnect applications

Thomas, M.E.; Sekigahama, S.; Renteln, P.; Pierce, J.M.; VLSI Multilevel Interconnection Conference, 1990. Proceedings., Seventh Int IEEE, 12-13 Jun 1990

Page(s): 438 -440

### [Abstract] [PDF Full-Text (180 KB)] IEEE CNF

### 13 Characterization of mechanical planarization processes

Renteln, P.; Thomas, M.E.; Pierce, J.M.;

VLSI Multilevel Interconnection Conference, 1990. Proceedings., Seventh Int IEEE , 12-13 Jun 1990

1000 , 12-13 Juli 1

Page(s): 57 -63

### [Abstract] [PDF Full-Text (324 KB)] IEEE CNF

14 An advanced single-level polysilicon submicrometer BiCMOS techr Brassington, M.P.; El-Diwany, M.H.; Razouk, R.R.; Thomas, M.E.; Tuntasooa Electron Devices, IEEE Transactions on , Volume: 36 Issue: 4 , Apr 1989 Page(s): 712 -719

#### [Abstract] [PDF Full-Text (1072 KB)] IEEE JNL

# 15 The potential of using refractory metals and barrier layers to gene temperature interconnects

Thomas, M.E.; Hartnett, M.P.; McKay, J.E.; Kapoor, A.K.; Chinn, J.D.; VLSI Multilevel Interconnection Conference, 1988. Proceedings., Fifth InternIEEE, 13-14 Jun 1988

Page(s): 183 -190

### [Abstract] [PDF Full-Text (540 KB)] IEEE CNF

### 1 <u>2 [Next]</u>

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved